

Beamlines at UVSOR

Beamline	Monochromator / Spectrometer	Energy Range					Targets	Techniques	Contact
BL1U	Light Source Development Gamma-ray FEL	2.5 - 82 eV						Irradiation (UV and Gamma-rays)	Y. Taira yostaira@ims.ac.jp
BL1B	Martin-Puplett FT-FIR	0.5 - 30 meV					Solid	Reflection Absorption	K. Tanaka k-tanaka@ims.ac.jp
BL2A	Double crystal	800 - 4 keV					Solid	Reflection Absorption	F. Matsui matui@ims.ac.jp
BL2B	18-m spherical grating (Dragon)	23 - 205 eV					Solid	Photoemission	S. Kera kera@ims.ac.jp
BL3U	Varied-line-spacing plane grating (Monk-Gillieson)	60 - 800 eV					Gas Liquid Solid	Absorption Photoemission Photon-emission	H. Iwayama iwayama@ims.ac.jp
BL3B	2.5-m off-plane Eagle	1.7 - 31 eV					Solid	Reflection Absorption Photon-emission	F. Matsui matui@ims.ac.jp
BL4U	Varied-line-spacing plane grating (Monk-Gillieson)	55 - 770 eV					Gas Liquid Solid	Absorption (Microscopy)	T. Araki araki@ims.ac.jp
BL4B	Varied-line-spacing plane grating (Monk-Gillieson)	25 eV - 1 keV					Gas Solid	Photoionization Photodissociation Photoemission	H. Iwayama iwayama@ims.ac.jp
BL5U	Varied-line-spacing plane grating (Monk-Gillieson)	20 - 220 eV					Solid	Photoemission	K. Tanaka k-tanaka@ims.ac.jp
BL5B	Plane grating	6 - 600 eV					Solid	Calibration Absorption	K. Tanaka k-tanaka@ims.ac.jp
BL6U*	Variable-included-angle varied-line-spacing plane grating	40 - 700 eV					Solid	Photoelectron Momentum Microscopy	F. Matsui matui@ims.ac.jp
BL6B	Michelson FT-IR	4 meV - 2.5 eV					Solid	Reflection Absorption IR microscope	K. Tanaka k-tanaka@ims.ac.jp
BL7U	10-m normal incidence (modified Wadsworth)	6 - 40 eV					Solid	Photoemission	K. Tanaka k-tanaka@ims.ac.jp
BL7B	3-m normal incidence	1.2 - 25 eV					Solid	Reflection Absorption Photon-emission	F. Matsui matui@ims.ac.jp

Yellow columns represent undulator beamlines.

***In-house beamlines**